

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: HASEGAWA, et al.

Serial No.: Not yet assigned

Filed: January 23, 2004

For: FABRICATION METHOD OF SEMICONDUCTOR INTEGRATED
CIRCUIT DEVICE AND MASK FABRICATION METHOD

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

January 23, 2004

Sir:

In the matter of the above-identified application, applicants are submitting herewith a copy of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

This information disclosure statement is being submitted with the new application.

Although some of the documents listed on the attached form equivalent to Form PTO-1449 are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language version of a patent family member; English language abstract or the discussion of the documents in the specification.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (Case: 843.43427X00), and please credit any excess fees to such deposit account.

Respectfully submitted,

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Attachments

Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 843.43427X00	SERIAL NO.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		APPLICANT HASEGAWA, et al.	
		FILING DATE January 23, 2004	GROUP

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date
AA	2003/0109126	06/12/2003	TERASAWA, et al.	438	612	08/15/2001
AB	6,656,645	12/02/2003	TANAKA, et al.	430	5	08/09/2001
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AF	2003/0180670	09/25/2003	HASEGAWA, et al.	430	494	07/28/2001
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						Yes	No
AM	5-289307	11/05/1993	JP	G03F	1/08	X	
AN	2002-62634	02/28/2002	JP	G03F	1/08	X	
AO	2002-118049	04/19/2002	JP	H01L	21/027	X	
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AR	2003-287875	10/10/2003	JP	G03F	1/08	X	
AS	2002-23340	01/23/2002	JP	G03F	1/08	X	
AT							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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AX	
AY	
AZ	
Examiner	Date Considered